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PATENT

Docket No.: 2336-257

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Inventor(s): Seung Wan CHAE et al.

Confirmation No. 2845

U.S. Patent Application No. 10/811,808

Group Art Unit: 2814

Filed: March 30, 2004

Examiner: WAI SING LOUIE

For:

GALLIUM NITRIDE (GaN)-BASED SEMICONDUCTOR LIGHT EMITTING DIODE AND

METHOD FOR MANUFACTURING THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required. For the examiners information the references listed on the attached PTO/SB/08A were cited in closely related Application No. 10/812,015.

Respectfully submitted,

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Date: July 28, 2006

CITATION IN AN APPLICATION (PTO/SB/O8A) U.S. PATENT			ATTY. DOCKET 2336-257	NO.	U.S. PATENT APPLICATION NO. 10/811,808	
			APPLICANT Seung Wan CHAE et al.			
			FILING DATE March 30, 2004		GROUP 2814	
EXAMINER'S			DOCUMENTS			FILING
INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	DATE
	2001/0002139	05-2001	Hiraoka, Keiko			
	6,117,700	09-2000	Orita et al.			
					 	
						
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		FOREIGN PATE	NT DOCUMENTS			
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	Abstract	Translation	Equivalent
INTIALO	10/173224	6/1998	Japan		X	
	09/129919	5/1997	Japan		X	
	10/173222	6/1998	Japan		X	
	2001-035796	2/2001	Japan		X	
	09-129933	5/1997	Japan		X	
	10-341039	12/1998	Japan		X	
	08-032115	2/1996	Japan		X	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.